University of HUDDERSFIELD International Institute for Accelerator Applications

# Modeling accelerator reliability

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# Overview



- ADS & Accelerator reliability
- How to approach reliability
- Modeling reliability
- Results
- Next steps

#### Accelerator Driven Sub-critical Reactor

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- Beam trips significant neutron flux driver in a ADS reactor
- Beam trips have two major consequences for the target:
  - thermal shock
  - for commercial operation of an ADS to be viable high machine availability is required. In energy production every second the reactor is not producing electricity at the contracted level the operator is fined
- Also prediction of beam trips needed for
  - Maintenance scheduling
  - Spare parts procurement

#### ADS Technology Readiness Assessment

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#### Transmutation Industrial-Scale P o w e r Demonstration Transmutation Generation Front-End System Performance Reliability A c c e l e r a t i n g RF Structure Development and Performance System Linac Cost Optimization Reliability **RF** Plant Performance Cost Optimization Reliability Performance Beam Delivery Performance Target Systems Reliability Instrumentation Performance and Control **Beam Dynamics** Emittance/halo growth/ beamloss Lattice design Reliability Rapid SCL Fault Recovery System Reliability **Engineering Analysis**

\*Accelerator and Target Technology for Accelerator Driven Transmutation and Energy Production. 2010. DOE sponsored White Paper on Technology for Accelerator Driven Systems. Green: "ready", Yellow: "may be ready, but and Energy Production. 2010. DOE demonstration or further analysis is required", Red: "more development is required"

#### ADS & Accelerator Reliability Requirements

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• Downtime requirements\*:

			Industrial Scale	Industrial Scale	
	Transmutation	Industrial Scale	Power Generation	Power Generation	
	Demonstration	Transmutation	with Energy Storage	without Energy Storage	
Beam trips	N / A	< 25000/vear	< 25000/vear	< 25000/voor	
(t < 1  sec)	N/ A	< 20000/ year	< 200007 year	< 20000/year	
Beam trips	< 2500/voor	< 2500/voor	< 2500/voor	< 2500/voar	
$(1 < t < 10~{\rm sec})$	< 2000/ year	< 2000/ year	< 2000/ year	< 2000/ year	
Beam trips	< 2500/voor	< 2500/voor	< 2500/voor	< 250/vear	
(10  s < t < 5  min)	< 2000/ year	< 2000/ year	< 2000/ year	< 200/ year	
Beam trips	< 50/year	< 50/year	< 50/vear	< 3/vear	
(t > 5 min)	< objycat		< 00/ year	< 5/year	
Availability	> 50%	> 70%	> 80%	> 85%	

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### ADS & Accelerator Reliability Numbers

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- SINQ (PSI):
  - 2000: the number of short beam trips at roughly 50 per day (t < 3 min)</li>
  - 2006 (August 14 to December 21):
    - 5500 trips of (t < 1 minute) and
    - 570 interrupts of (t < 8 hours)
- SNS (ORNL):
  - 2010:
    - Daily about 100 trips per day of duration (1 s < t < 1 minute) and
    - Daily 10 trips of duration (1 min < t < 1 hour)
  - 2013:
    - a daily average of about 40 trips of duration (t < 1 minute)</li>

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# Predictive methodologies

- Top-Down / Deductive
  - Need detailed info about components and connections
  - Need "solid" database of components
  - Most common: Reliability Block Diagram (RBD)
    - Layout of RBD usually depends on system state!
  - Fault Tree Analysis (FTA)
    - Determine all component faults that lead to given system fault
- Bottom-Up / Inductive
  - Failure Mode and Effects (Criticality) Analysis (FMEA/FMECA)
    - Can be performed with expert judgment on relative criticality of components
    - Can be performed also with less detail in design

#### Addressing Accelerator Reliability

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During design stage

- Predictive methods, design change

- After finished construction
  - Statistical analysis or performance, parts replacement



#### During design phase

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 Reliability Block Diagrams, Fault Tree Analysis, Failure Mode and Effects Analysis,



# Why different approach

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- Accelerator reliability is not yet fully defined, understood nor addressed, but there is data that is retrievable from modern operating accelerators that contains detailed information about the accelerator behavior.
- Analyzing this data could provide insight and yield results that classical approaches (e.g. RBDs) struggle with due to the lack of good quality data.
- Accelerators are very complex, too complex to be able to model every detail
  - Data-centric approach
  - Use system-agnostic data (e.g. beam current)
- Instead of "more precision, less accuracy" in modeling reliability "more observation, more predictability"?

# Recent developments

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- AvailSim, Monte Carlo simulations
- Markov chains sensitivity analysis
- Predictive data-centric models

Figure 3: Example of prognostics output.

### SNS Beam Current Signal

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Pulse time

# Emergent behavior

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- Complex accelerator system has 1000's of interconnected devices
- These devices connected and running together generate an unique signature (e.g. beam current)
- Changes in operation of the accelerator is caused by one (or more) devices changing behavior (e.g. sub-optimal performance or malfunction)
- Question: Can this change be detected in the unique signature?
- Answer: Most probably yes
- Example:
  - The national power grid is a large system of 1000's of interconnected devices (producers, consumers, distribution grid, transformers etc.)
  - The unique signature of the current distributed by national power grids is used in acoustic forensics to identify and verify when recordings are made

#### Electric Network Frequency Criterion

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# **ENF** Criterion

- Create databases of certain pulse types:
  - Pre-trip: dataset of last successful pulses before the machine tripped
  - Normal operation: dataset of pulses from normal operation
- Matching algorithms:
  - Minimum Root Mean Squared (RMS)  $RMS(x,y) = E_{rms} = \sqrt{\frac{\sum_{i=1}^{L} (x[i] y[i])^2}{L}}$
  - Maximum Correlation coefficient (CC)
- Procedure

$$CC(x, y) = \frac{\sum_{i=i}^{L} (x[i] - \bar{x})(y[i] - \bar{y})}{(L-1)\sigma_{\tau}\sigma_{\tau}}$$

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- Calculate RMS, CC values for sample and databases
- If threshold is reached, match is detected
- Depending on match type:
  - Pulse is pre-trip = high probability the machine will trip the next pulse
  - Pulse is normal operation = next pulse will not trip the machine

# Initial results

- The setup
  - 2 databases: Pre-trip, normal operation
  - 5 days of SNS trip data:
    - 1200 pulses
    - 18M datapoints
- Matching samples
  - 100 pre-trip pulses
  - 100 normal operation pulses

#### Percentage of successful matches per pulse type

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Method	Correct	False	As both	Not identified
RMS	11.1%	8.1%	8.1%	72.7%
MCC	6.1%	21.2%	17.2%	55.5%

TABLE 6. Previous sample matching results, percentage of all samples

Method	Correct	False	As both	Not identified
RMS	28.0%	7.0%	39.0%	26.0%
MCC	50.0%	0.0%	33.0%	17.0%

TABLE 7. Next sample matching results, percentage of all samples



### Next steps



- Refine ENF matching algorithms
  - Use higher fidelity data, bunch-by-bunch matching
- Stochastic Hidden Markov Models (HMM)
  - Models are trained on sets of data to be able to recognize patterns
  - Example: speech recognition
  - Leverage knowledge base from speech and pattern recognition
  - Test on datasets we have, compare results ENF results

# Summary



- The drive of research is the future industrial application of accelerators
- Adopt a data-centric, system-agnostic approach
- Reliability can be improved by predicting failures, not only by designing them away
- Reliability as a discipline is well advanced in industry, but not in accelerator field
- Looking at predicting behavior using analytical and stochastic methods to evaluate if this can give vital needed seconds for accelerators to be used in an industrial setting

# Acknowledgments

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 Big thanks to Wim Blockland from SNS for sharing the data that makes this research possible.



## Thank you!